Power MOSFET

30 V, 85 A, Single N-Channel, SO-8FL

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- Thermally Enhanced SO-8 Package
- These are Pb-Free Devices*

Applications

- Refer to Application Note AND8195/D
- CPU Power Delivery
- DC-DC Converters
- Low Side Switching

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V_{DSS}	30	V
Gate-to-Source Voltage		V_{GS}	±16	V	
Continuous Drain Current R _{θJA}		$T_A = 25^{\circ}C$ $T_A = 85^{\circ}C$	Ι _D	18 13	Α
(Note 1) Power Dissipation R _{0.IA} (Note 1)		T _A = 25°C	P _D	2.21	W
Continuous Drain Current R _{θJA} ≤ 10 sec		T _A = 25°C	I _D	29.5 21	A
Power Dissipation $R_{\theta JA}$, $t \le 10$ sec	Steady	T _A = 25°C	P _D	5.8	W
Continuous Drain Current R _{θJA}	State	$T_A = 25^{\circ}C$ $T_A = 85^{\circ}C$	Ι _D	11.5 8.2	Α
(Note 2) Power Dissipation R _{θJA} (Note 2)		T _A = 85 °C	P _D	0.88	W
Continuous Drain Current R _{θJC} (Note 1)		$T_C = 25^{\circ}C$ $T_C = 85^{\circ}C$	I _D	85 61	Α
Power Dissipation R _{θJC} (Note 1)		T _C = 25°C	P _D	48.1	W
Pulsed Drain Current	t _p =10μs	T _A = 25°C	I _{DM}	170	Α
Current limited by pa	ackage	T _A = 25°C	I _{Dmaxpkg}	100	Α
Operating Junction and Storage Temperature		T _J , T _{STG}	-55 to +150	°C	
Source Current (Body Diode)		I _S	48	Α	
Drain to Source dV/dt			dV/dt	6	V/ns
Single Pulse Drain-to-Source Avalanche Energy (V_{DD} = 50 V, V_{GS} = 10 V, I_{L} = 33 A_{pk} , L = 0.3 mH, R_{G} = 25 Ω)			EAS	163	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

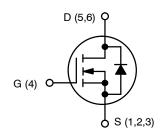
Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.



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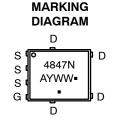
http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
30 V	4.1 mΩ @ 10 V	0F A
30 V	6.2 mΩ @ 4.5 V	85 A



N-CHANNEL MOSFET





A = Assembly Location

Y = Year WW = Work Week • Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMFS4847NT1G	SO-8FL (Pb-Free)	1500 / Tape & Reel
NTMFS4847NT3G	SO-8FL (Pb-Free)	5000 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

^{*}For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	2.6	
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	56.6	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	142	*C/VV
Junction-to-Ambient - t ≤ 10 sec	$R_{ heta JA}$	21.6	

- Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size.

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS						1	
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				25		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V, V _{DS} = 24 V	T _J = 25 °C			1	
			T _J = 125°C			10	μΑ
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} = ±16 V				±100	nA
ON CHARACTERISTICS (Note 3)						•	•
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D$	= 250 μΑ	1.45	1.8	2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.2		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V to 11.5 V	I _D = 30 A		3.2	4.1	_
			I _D = 15 A		3.2		
		V _{GS} = 4.5 V	I _D = 30 A		5.0	6.2	mΩ
			I _D = 15 A		5.0		1
Forward Transconductance	9FS	V _{DS} = 1.5 V, I _D = 30 A			74		S
CHARGES AND CAPACITANCES							
Input Capacitance	C _{ISS}				2614		
Output Capacitance	C _{OSS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 12 V			466		pF
Reverse Transfer Capacitance	C _{RSS}				241		
Total Gate Charge	Q _{G(TOT)}				19.2	28	<u>† </u>
Threshold Gate Charge	Q _{G(TH)}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$			1.6		nC
Gate-to-Source Charge	Q_{GS}				7.3		
Gate-to-Drain Charge	Q_{GD}				6.1		
Total Gate Charge	Q _{G(TOT)}	$V_{GS} = 11.5 \text{ V}, V_{DS} = 15 \text{ V},$ $I_{D} = 30 \text{ A}$			43.8		nC
SWITCHING CHARACTERISTICS (Note 4)							
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 4.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			17.7		ns
Rise Time	t _r				53		
Turn-Off Delay Time	t _{d(OFF)}				21		

- 3. Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.
- 4. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS ($T_J = 25$ °C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 4)						
Turn-On Delay Time	t _{d(ON)}			10.5		ns	
Rise Time	t _r	V_{GS} = 11.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			20.8		
Turn-Off Delay Time	t _{d(OFF)}				28.1		
Fall Time	t _f				6.5		
DRAIN-SOURCE DIODE CHARACTE	RISTICS						
Forward Diode Voltage	V _{SD}	V _{GS} = 0 V, I _S = 30 A	T _J = 25°C		0.8	1.0	.,
			T _J = 125°C		0.7		V
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 30 \text{ A}$			15.4		ns
Charge Time	t _a				8.2		
Discharge Time	t _b				7.2		
Reverse Recovery Charge	Q _{RR}				6.0		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L _S	- - T _A = 25°C			0.93		nH
Drain Inductance	L _D				0.005		1
Gate Inductance	L _G				1.84		
Gate Resistance	R_{G}				0.9		Ω

^{3.} Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.

TYPICAL CHARACTERISTICS

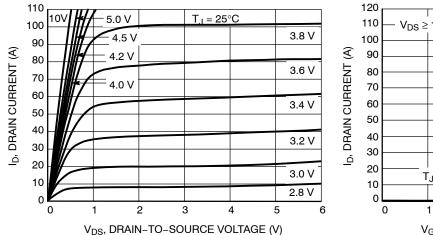


Figure 1. On-Region Characteristics

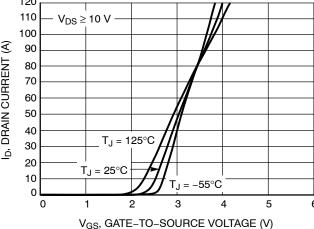
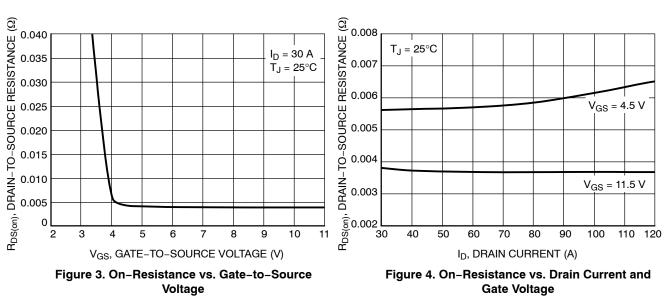


Figure 2. Transfer Characteristics

^{4.} Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS



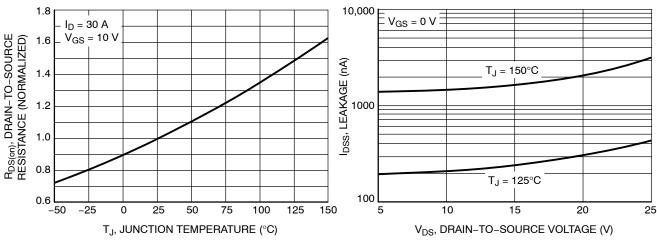


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

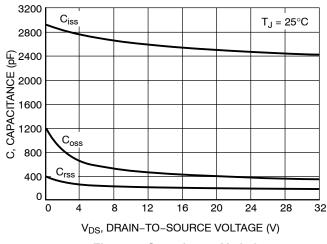


Figure 7. Capacitance Variation

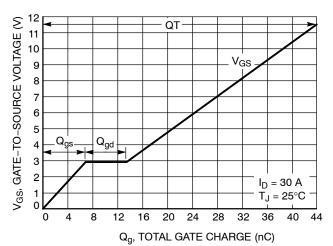


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

TYPICAL CHARACTERISTICS

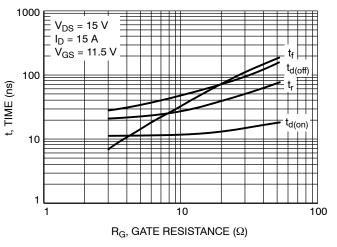


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

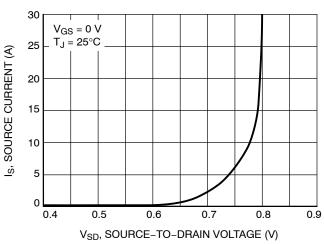


Figure 10. Diode Forward Voltage vs. Current

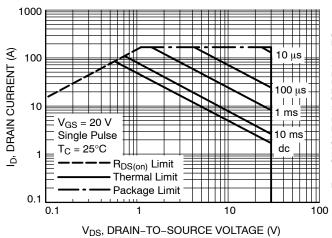
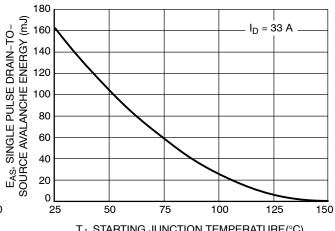


Figure 11. Maximum Rated Forward Biased



T_J, STARTING JUNCTION TEMPERATURE (°C)

Safe Operating Area

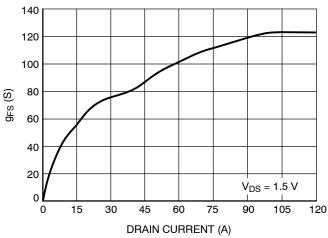


Figure 13. g_{FS} vs. Drain Current



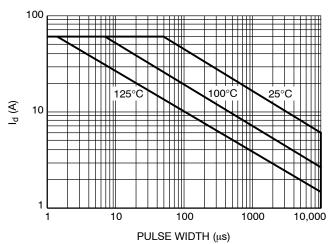
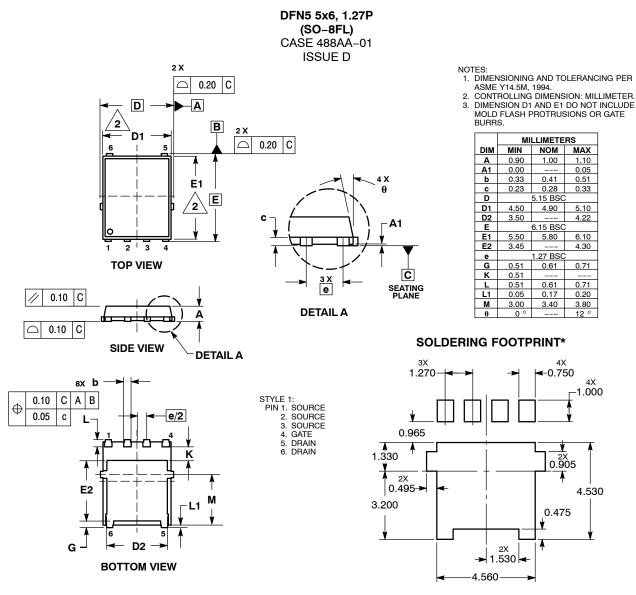


Figure 14. I_d vs. Pulse Width

PACKAGE DIMENSIONS



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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